

FIG. 1

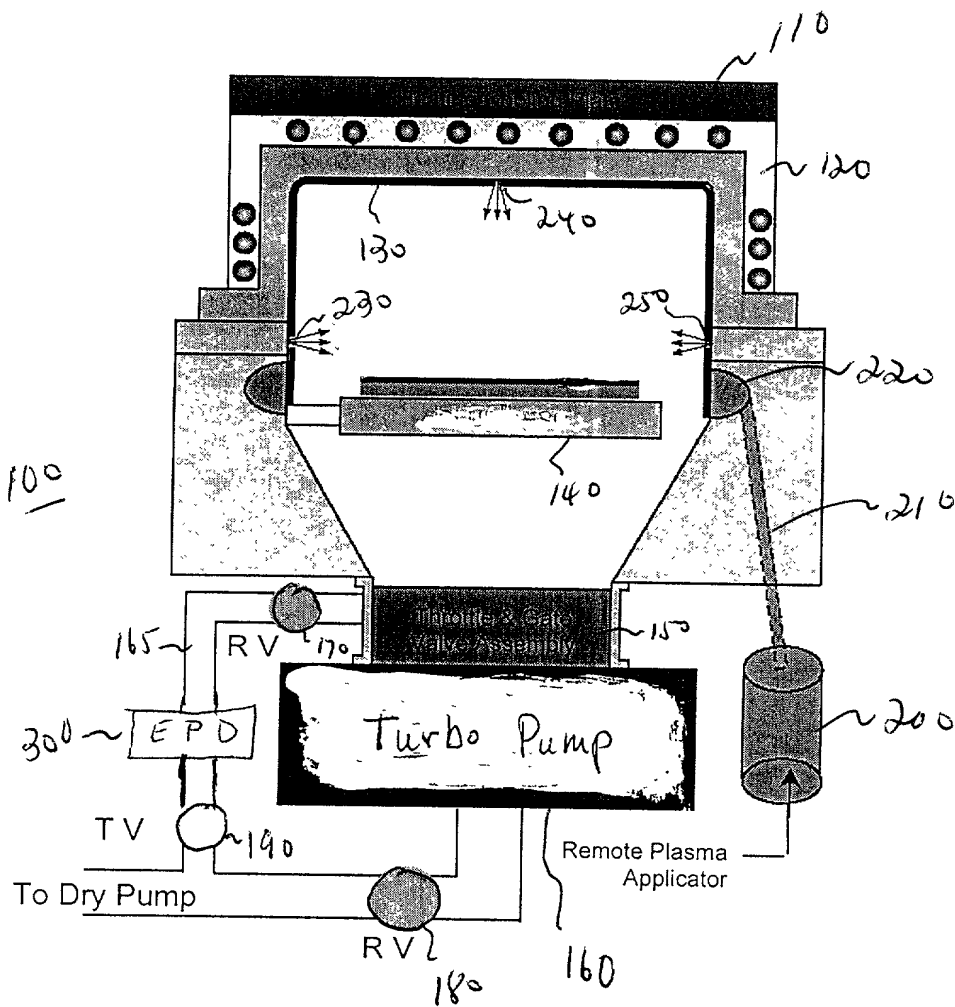


FIG. 2

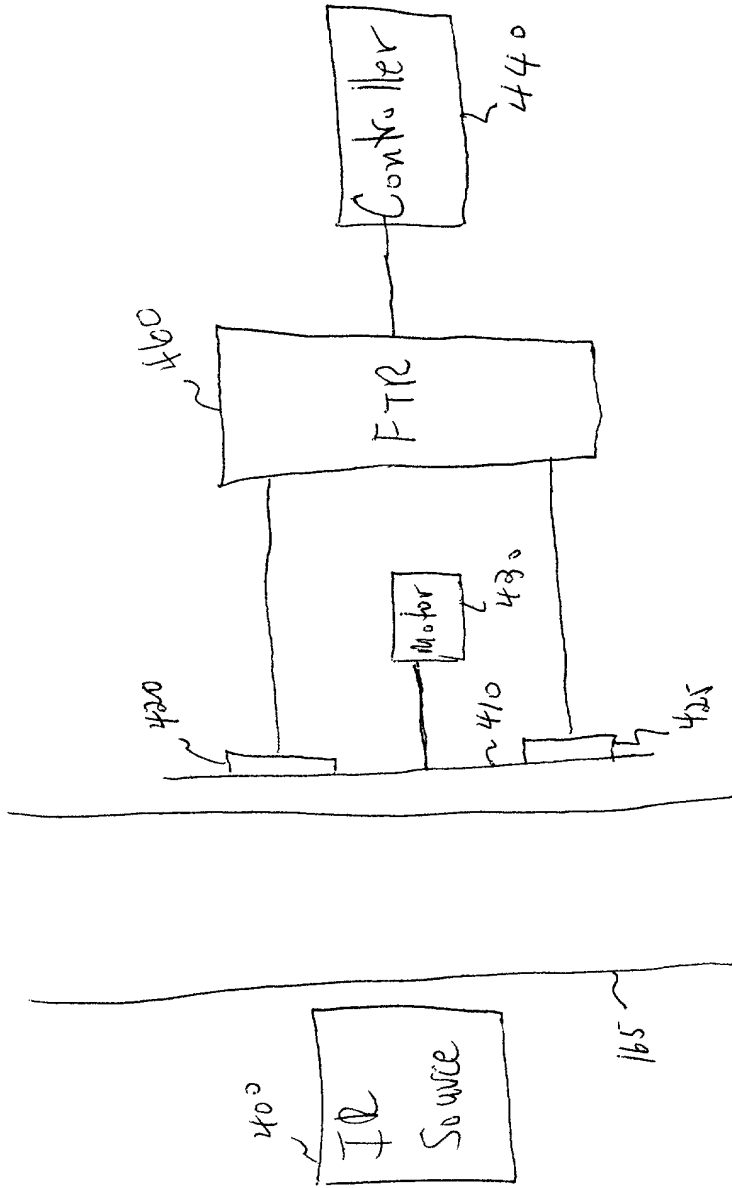


FIG. 3

United States Patent

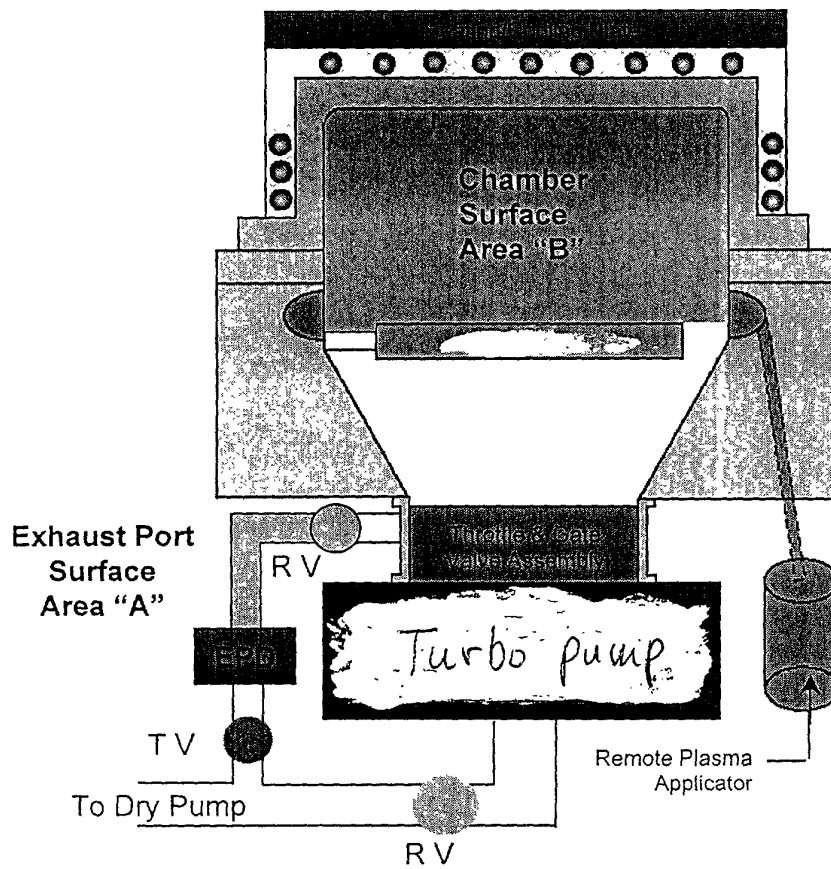


FIG. 4

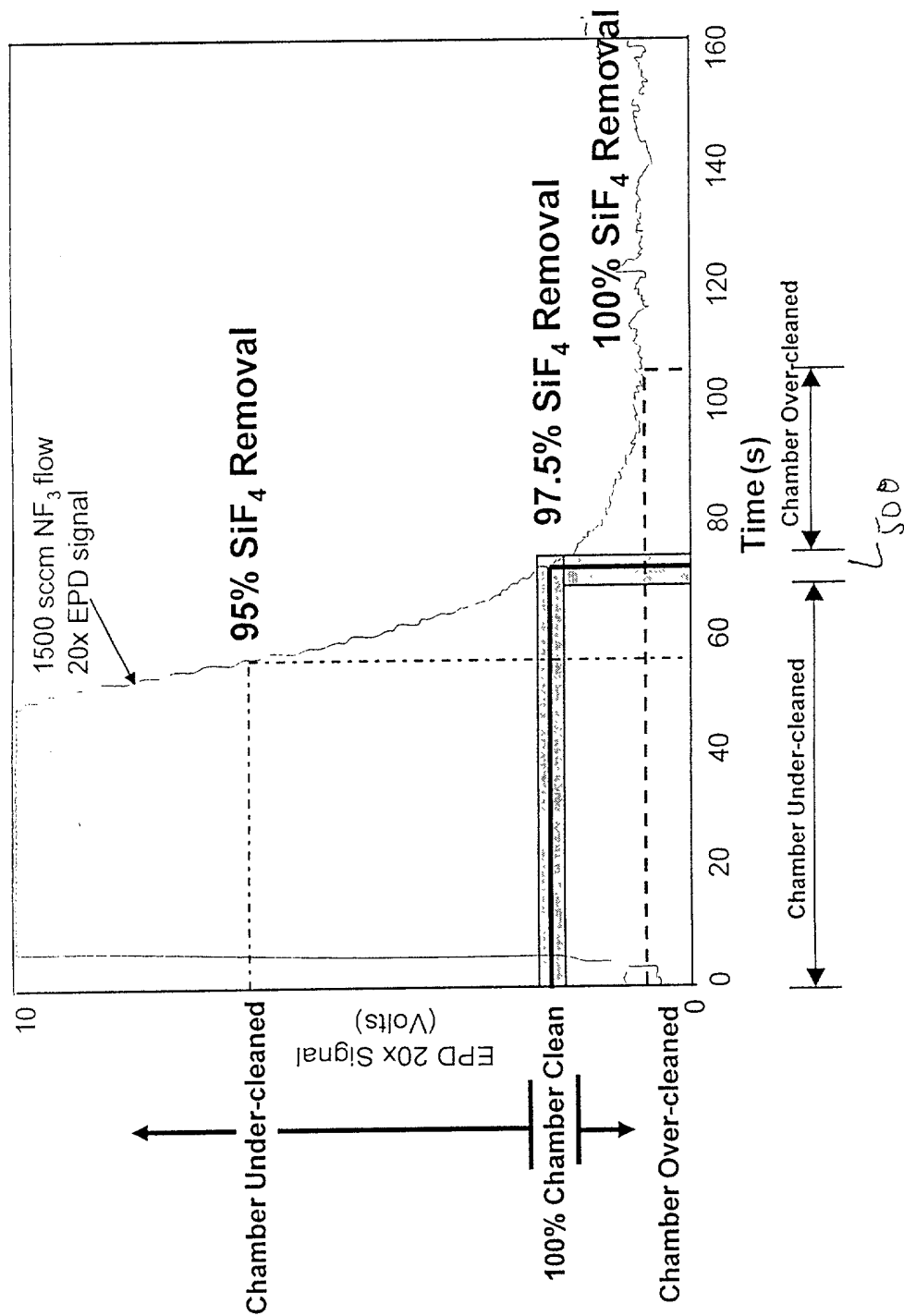


FIG. 5

# Effect of Chamber Under / Over-clean on Particle Adders

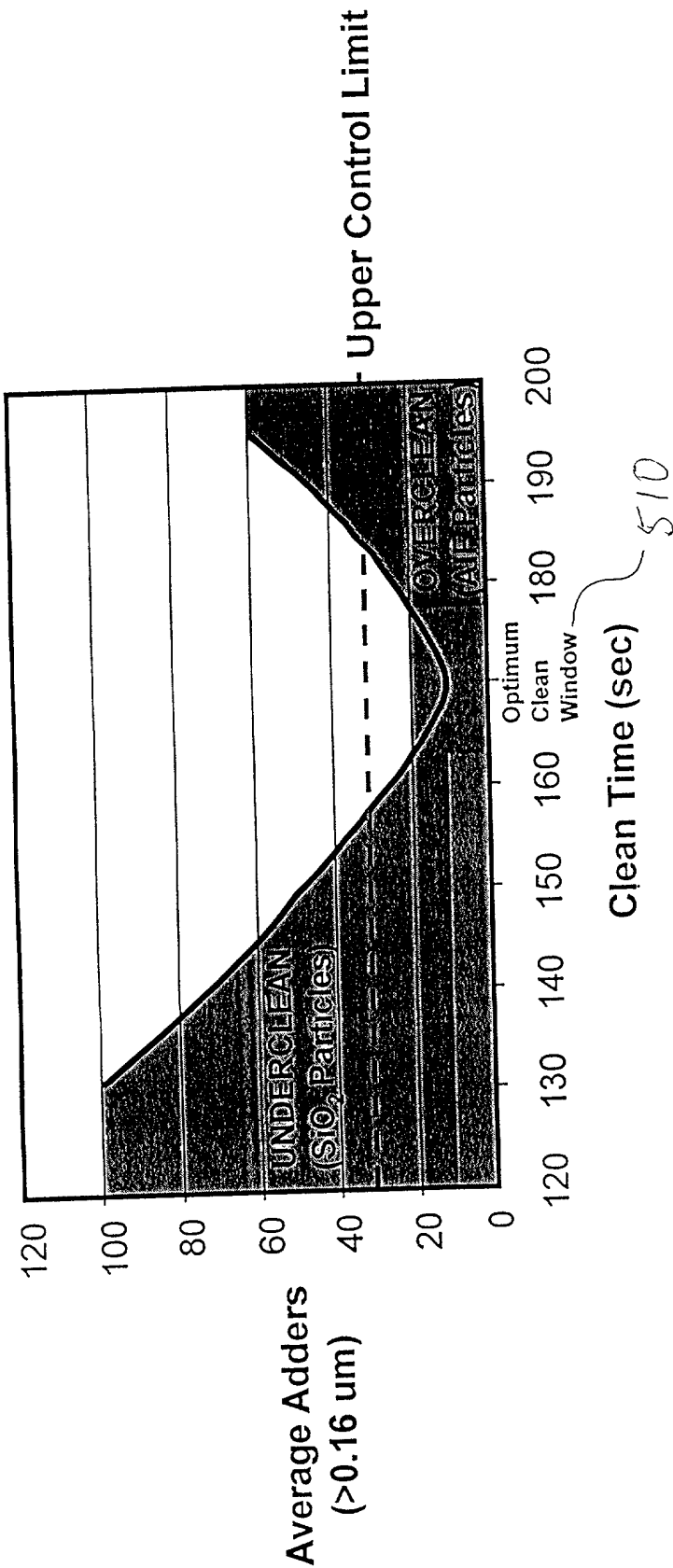


FIG. 6